

**Semiconductor Device Modeling**  
**Prof. Shreepad Karmalkar**  
**Department of Electrical Engineering**  
**Indian Institute of Technology- Madras**

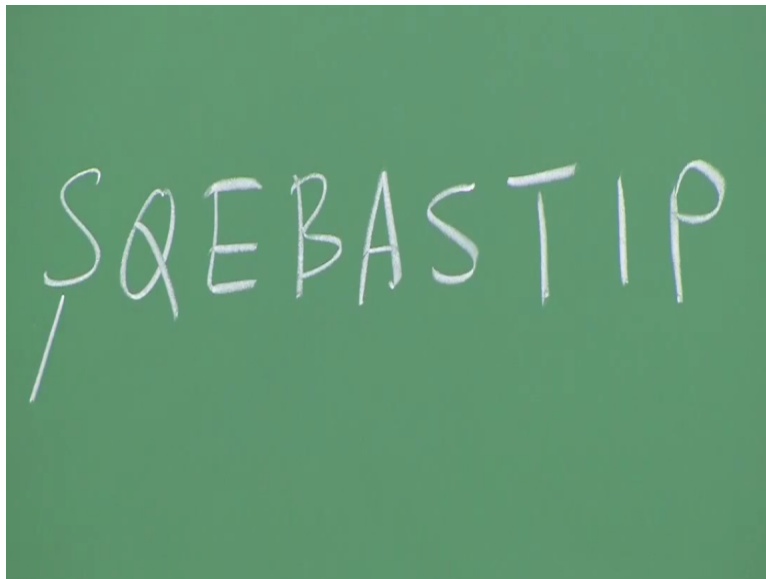
**Lecture - 41**

**DC Model of a Large Uniformly Doped Bulk MOSFET: Qualitative Theory**

In this module, we begin a discussion of the DC model of a large uniformly doped bulk MOSFET. In the previous module, we remarked that a modern MOSFET is a small geometry device with substrate atoms arranged randomly. However, to model this device we go about in a series of steps in which the starting point is a large geometry device with uniform substrate doping.

So that is what we are going to start with now. Now we have remarked that there are 9 steps in deriving model for any set of device characteristics.

**(Refer Slide Time: 01:10)**



The 9 steps are SQEBASTIP. In the previous module, we discussed the structure and characteristics of the MOSFET. Now once we know what is our goal? What are the characteristics we want to model? We can begin with the qualitative theory. Now that is what is the topic of this particular module.

**(Refer Slide Time: 01:39)**

## Module 10

### DC Model of a Large Uniformly doped Bulk MOSFET: Qualitative Theory

At the end of this module, you should be able to do the following for a bulk MOSFET with uniform substrate doping and large  $L$ ,  $W$ ,  $t_{ox}$  under steady state

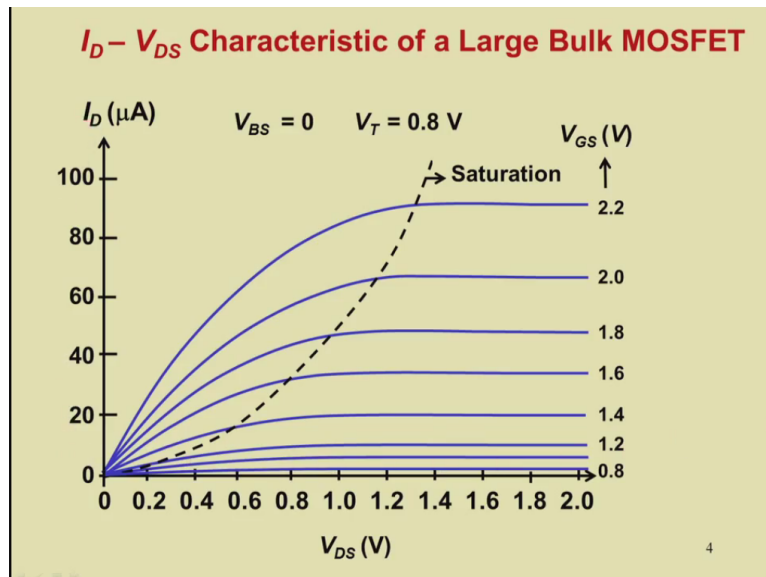
- explain the shape of the  $I_D-V_{DS}$ ,  $I_D-V_{GS}$  and  $I_B-V_{GS}$  curves in terms of the charge and field conditions in the device

At the end of this module, you should be able to do the following for a bulk MOSFET with uniform substrate doping and large  $L$  that is channel length,  $W$  that is channel width,  $t_{ox}$  that is oxide thickness under steady state conditions. First, we must be able to explain the shape of the  $I_D-V_{DS}$ ,  $I_D-V_{GS}$ , and  $I_B-V_{GS}$  curves in terms of the charge and field conditions in the device.

Now note here, we are talking about drain current, we are talking about bulk current or substrate current, but we are not talking about the gate current. Now the reason for this is we are considering a device with thick oxide and if the insulator is thick then the leakage current through that is very small. That is the reason why we are not considering the behavior of the gate leakage.

Now let us look at the shapes of  $I_D-V_{DS}$ ,  $I_D-V_{GS}$ , and  $I_B-V_{GS}$  curves, which were introduced in the previous module.

**(Refer Slide Time: 02:50)**



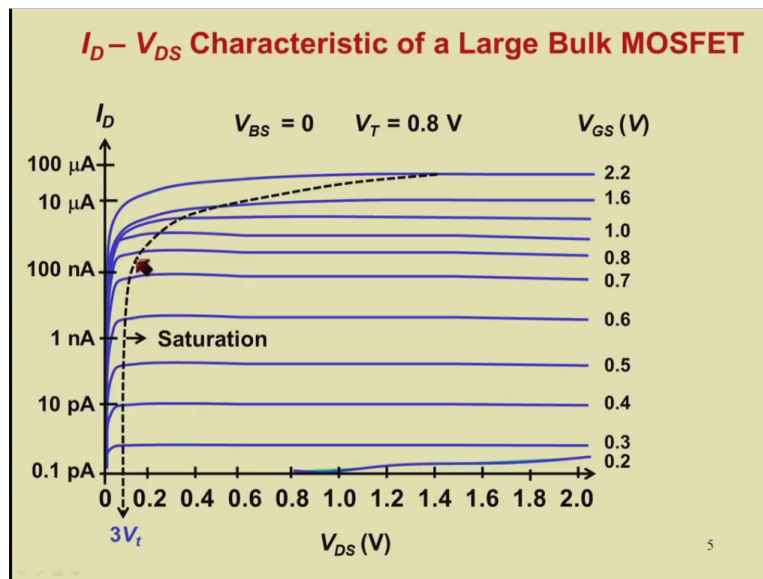
This is a  $I_D - V_{DS}$  map. The important features here are that the drain current rises as you increase the  $V_{DS}$  and progressively the rise tapers off and beyond some point the current becomes almost constant. This is the saturation region. Now the point at which saturation happens are the value of  $V_{DS}$  at which the current saturates goes on increasing as  $V_{GS}$  increases.

So you can see here this is increasing  $V_{GS}$  and the value of  $V_{DS}$  at which saturation occurs is going on increasing. Now when you plot the current  $I_D$  on a linear scale, you cannot expand the portion of the characteristics for  $V_{GS}$  less than threshold voltage that is 0.8 volts.  $V_T = 0.8$  volts for this device. Now the current for  $V_{GS} < V_T$  that is 0.8 is important though it is small.

You know that in any circuit the memory of the logic levels 1 or 0 is stored in terms of the charge on a capacitor. Now if the device connecting to a charge capacitor is off, ideally the device should not leak any of the charge; however, in practice we know that even below gate source voltage = threshold voltage there is some small current that the MOSFET draws and this small current would leak the capacitor charge and it may change the logic level.

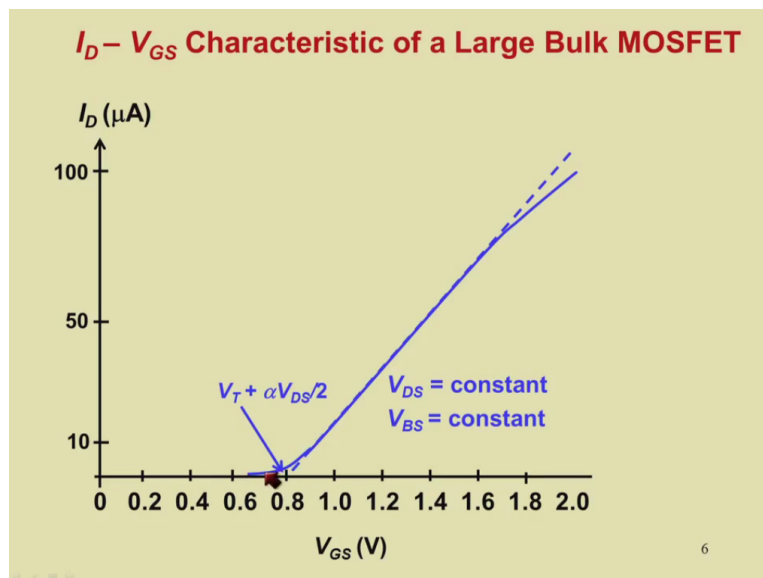
See in order that the logic level does not change and the memory is preserved, you may have to refresh the circuit periodically. Therefore, the amount of charge that leaks during the off state is important and that is why the characteristics of  $V_{GS} < V_{GS} = V_T$ . The characteristics of the drain current versus  $V_{DS}$  for  $V_{GS} < V_T$  is important. Now that can be shown if you change the drain current access to a log scale.

(Refer Slide Time: 05:05)



Now when you do that you can see here that the region  $V_{GS} < V_T$  is expanded a lot. The important feature to be observed here is that the increment in  $I_D$  on the log scale is uniform for uniform increment in  $V_{GS}$ , which means  $I_D$  versus  $V_{GS}$  is exponential for  $V_{GS} < V_T$ . So this is something we would like to explain. Another feature that you see is that the value of  $V_{DS}$  for which the current saturates is approximately constant at 3 times  $V_T$  for  $V_{GS} < V_T$ .

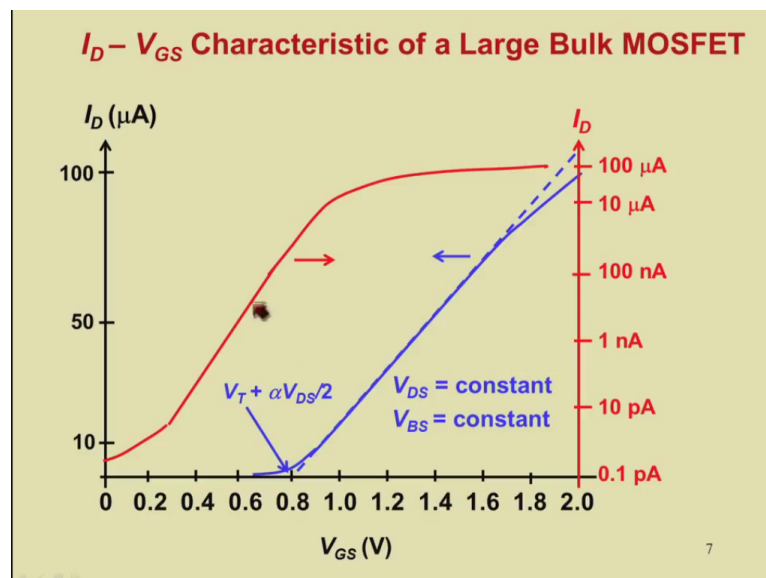
(Refer Slide Time: 05:49)



Let us look at the  $I_D$ - $V_{GS}$  curves that we have to explain in our qualitative model. The  $I_D$ - $V_{GS}$  curve shows a predominant linear region if extrapolate that linear region to the  $V_{GS}$  axis, you can get the value of voltage, which is threshold voltage plus a very small value dependent on  $V_{DS}$ . This formula we will explain later when we derive the  $I_D$ - $V_{DS}$ ,  $I_D$ - $V_{GS}$  equations.

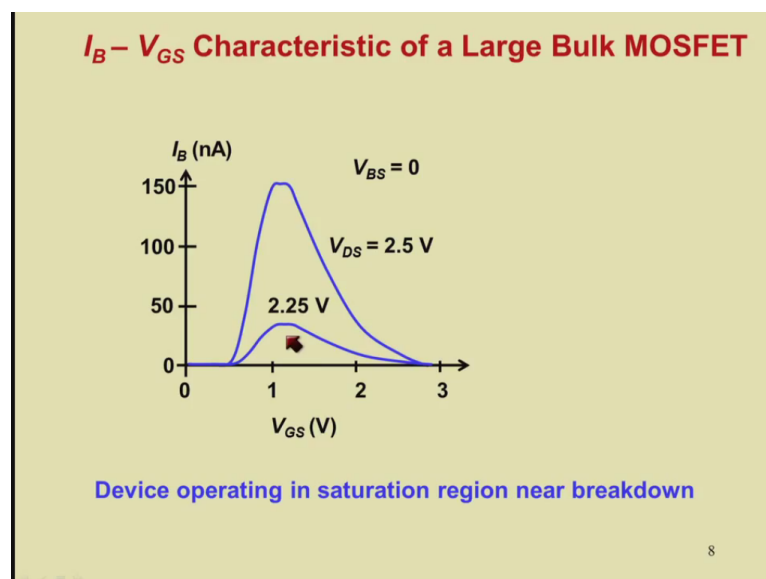
Now for large values of  $V_{GS}$ , the rate of rise of  $I_D$  tapers off a little bit and for values of  $V_{GS}$  around  $V_T$  you find that there is a rapid decrease in the current. Now to expand these current levels near  $V_T$  once again we use the same trick that we used for  $I_D$ - $V_{DS}$  characteristics.

(Refer Slide Time: 06:44)



We change the  $I_D$  axis to a log scale. Here you can see that the  $I_D$  as a function of  $V_{GS}$  is linear when the  $I_D$  is plotted on the log scale, which means  $I_D$ - $V_{GS}$  characteristics near  $V_{GS} = V_T$  that is this region are all exponential in nature  $I_D$  as the function of  $V_{GS}$  is exponential.

(Refer Slide Time: 07:12)

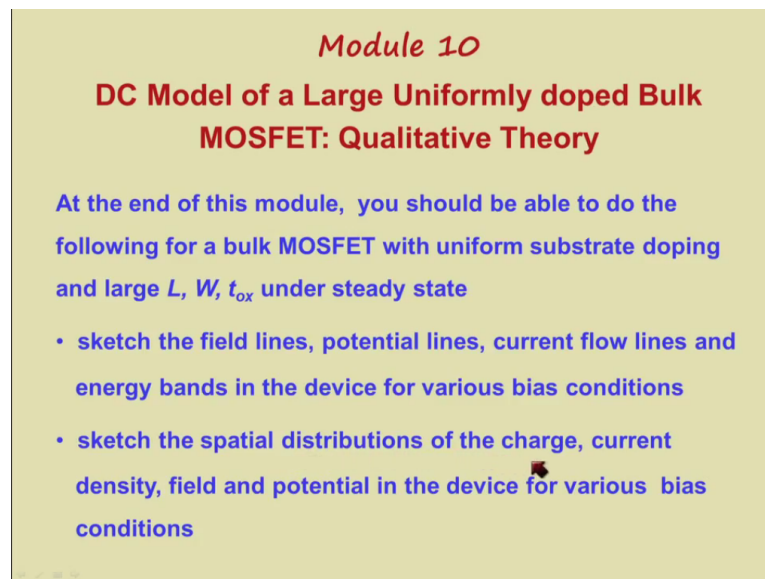


Now let us look at the shape of the  $I_B$ - $V_{GS}$  curves, which we introduced in the previous module. So the  $I_B$ - $V_{GS}$  curves are generally plotted for device operating in saturation region

near breakdown because for a device below breakdown the substrate current is not much. So near breakdown what you find is as you increase your VGS for a fixed VDS, the current rises beyond a certain voltage, reaches a peak and then falls off.

The peak occurs at approximately half the value of VDS. When increase in VDS, the current increases, but the shape remains the same. Let us see what other things we should be able to do at the end of this module.

**(Refer Slide Time: 08:07)**



*Module 10*

**DC Model of a Large Uniformly doped Bulk MOSFET: Qualitative Theory**

At the end of this module, you should be able to do the following for a bulk MOSFET with uniform substrate doping and large  $L$ ,  $W$ ,  $t_{ox}$  under steady state

- sketch the field lines, potential lines, current flow lines and energy bands in the device for various bias conditions
- sketch the spatial distributions of the charge, current density, field and potential in the device for various bias conditions

You should be able to sketch the field lines, potential lines, current flow lines and energy bands in the device for various bias conditions and finally you should be able to sketch the spatial distributions of the charge, current density, field and potential in the device for various bias conditions.

**(Refer Slide Time: 08:29)**

## Importance of a Qualitative Model

We discuss all the effects together at a qualitative level, before embarking on quantitative modeling of each of them, because, in order that a device model be realistic, it is more important to include all the significant effects than it is to accept a less realistic model and solve it accurately.

For a given device, all the different types of models discussed in Module 8 are derived based on the same qualitative theory.

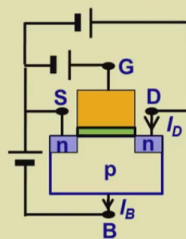
15

Now let us make a comment regarding the importance of a qualitative model. In qualitative modeling, we discussed all the effects together at a qualitative level before embarking on quantitative modeling of each of them because in order that a device model be realistic it is more important to include all the significant effects than it is to accept a less realistic model and solve it accurately.

For a given device, all the different types of models discussed in module 8 are derived based on the same qualitative theory. Now this is an important point that you have different types of models, but the qualitative theory underlying the various models is more or less the same.

**(Refer Slide Time: 09:17)**

## 2) Qualitative Model



Five ways of expressing a qualitative model for  $I_D$  and  $I_B$

- a) Tabulate the factors responsible for
  - creation and continuity of  $J_n$ ,  $J_p$ ,  $E$
  - boundary conditions on  $(n$  or  $J_n)$ ,  $(p$  or  $J_p)$ ,  $(\psi$  or  $E)$

21

Let us list out what are the things we need to do in qualitative modeling? First, we sketch device schematic showing the bias conditions. Let us consider an N-channel MOSFET. For

an N-channel MOSFET, the drain is positive with respect to source or rather whichever n contact is positive between the 2 n contacts that contact is the drain because in an N-channel MOSFET, the current flow is because of electrons.

The source provides the electrons and the drain collects. Now you know that the most positive terminal would collect the electrons. Therefore, the drain is positive with respect to source so that is this power supply. Now since you need electrons at the interface and the substrate is p-type, the only way you can achieve is if you make the gate positive with respect to source so that is what is indicated here.

Finally, you can have situations in a circuit when the bulk may get reverse biased with respect to the source and that is what is shown here. So these are the 3 power supplies okay.  $V_{DS}$ ,  $V_{GS}$  and  $V_{BS}$ . You have the drain current flowing into the drain because the electrons flow out of the drain and you have the bulk current flowing out of the bulk terminal. The reason why the bulk current flows out can be understood very easily considering the polarity of the drain and bulk.

The drain is positive with respect to bulk. Therefore, any current from drain to bulk for example should be in this direction. Same way you can argue about the source to bulk current right from the polarity of the bias here. Now what I am going to do is I am going to list out from a previous module in which we discussed the procedure for device modeling. The steps associated with qualitative modeling. So this is repetition from a previous module.

There are 5 ways of expressing a qualitative model for any characteristics. In this module, we are discussing the characteristics of the drain current and the bulk current of a MOSFET. What are the 5 ways? Now first, we should be able to tabulate the factors responsible for creation and continuity of electron current density, hole current density and electric field and we should tabulate the factors responsible for boundary conditions on carrier concentrations or the carrier current densities and potential or field.

That is  $n$  or  $J_n$ , any one of the 2 or any one of this pair  $p$  or  $J_p$  or any one of this pair  $\psi$  or  $E$ .  
**(Refer Slide Time: 12:30)**



### 2) Qualitative Model

Five ways of expressing a qualitative model for  $I_D$  and  $I_B$

b) Sketch the solution anticipated from the qualitative model, in the following form

- flow lines for  $J_n$ ,  $J_p$ ,  $E$  and equi-potential lines for  $\psi$
- plots of  $n$ ,  $p$ ,  $J_n$ ,  $J_p$ ,  $E$ ,  $\psi$ , energy bands with  $x$ ,  $y$

24

Apart from these 2 ways, the other ways are sketch the solution anticipated from the qualitative model in the following form, flow lines for  $J_n$ ,  $J_p$ ,  $E$  and equi-potential lines for  $\psi$  and plots of  $n$ ,  $p$ ,  $J_n$ ,  $J_p$ ,  $E$ ,  $\psi$  and energy bands with  $x$ ,  $y$  that means we must be able to sketch the spatial distribution of carrier concentrations, carrier current densities, electric field, potential and energy bands.

**(Refer Slide Time: 13:08)**

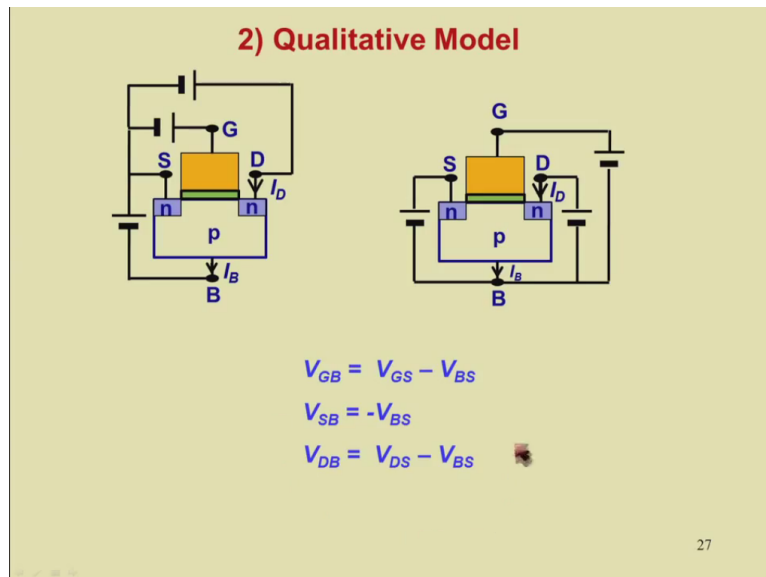
### 2) Qualitative Model

Five ways of expressing a qualitative model for  $I_D$  and  $I_B$

c) Tabulate the variables, constants and parameters of the model.

Now apart from these 4 ways, finally we should tabulate the variables, constants and parameters of the model.

**(Refer Slide Time: 13:21)**



Now let me repeat an important point. In circuit applications, the device is always biased with source as the common terminal. However, from the point of view of device modeling where we want to derive the expression for current as a function of the terminal voltages starting from device physics it proves more convenient to bias the various terminals of the device with respect to the bulk.

Now what is the advantage of biasing with respect to bulk? Here you can see that this power supply appears across these 2 terminals of the source bulk junction. This power supply here  $V_{DB}$  appears across the 2 terminals of the drain bulk junction and this power supply  $V_{GB}$  appears across the 2 terminals of the gate to bulk junction right. Now you know that it is easy to model the conditions of charge, current etc in the device as a function of the terminal voltage for any junction okay.

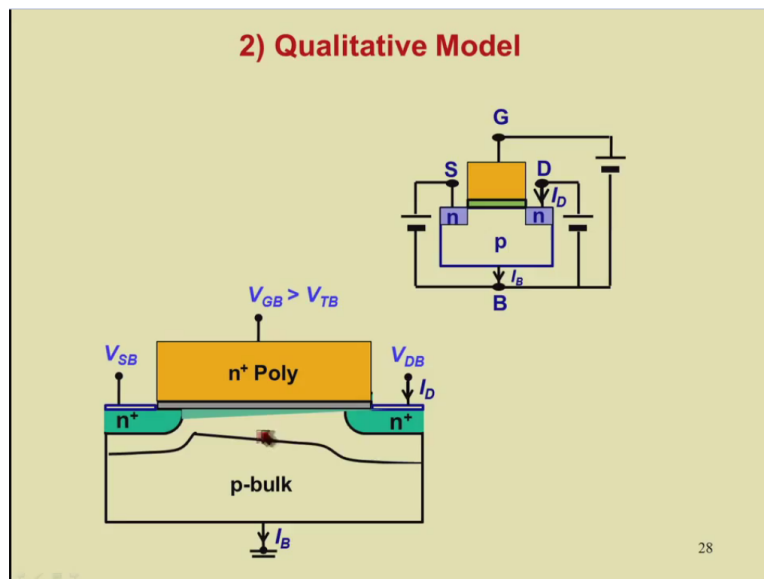
So here we can model a charge conditions directly in terms of terminal voltages on the junctions. On the other hand, if you compare it with this picture, here you find for example if you take the  $V_{DS}$ , the  $V_{DS}$  drops across series of 2 junctions, drain bulk and source bulk junction. So I will have to separate the  $V_{DS}$  into the voltages across these 2 junctions if I want to model a charge conditions in the device as a function of this.

Now same thing applies to  $V_{GS}$ . So  $V_{GS}$  and  $V_{SB}$  together will decide the voltage between gate and bulk. So when I want to model the charge conditions in the device as a function of  $V_{GS}$ , I will have to take into account  $V_{BS}$  also. Now this kind of complication is avoided when you consider all biases with respect to bulk. After we have derived the drain current  $I_D$

and  $I_B$  as a function of  $V_{GB}$ ,  $V_{DB}$  and  $V_{SB}$  we can always transform the equations to equations for  $I_D$  and  $I_B$  in terms of  $V_{DS}$ ,  $V_{GS}$  and  $V_{BS}$ .

These are the equations for doing so. So you take  $V_{GB}$  and replace the  $V_{GB}/V_{GS}-V_{BS}$ . Now similarly you have the other voltages,  $V_{SB} - V_{BS}$  and  $V_{DB}$  is  $V_{DS}-V_{BS}$ . So you can make this replacement in the equations derived then the characteristics will become a function of  $V_{GS}$ ,  $V_{BS}$  and  $V_{DS}$ .

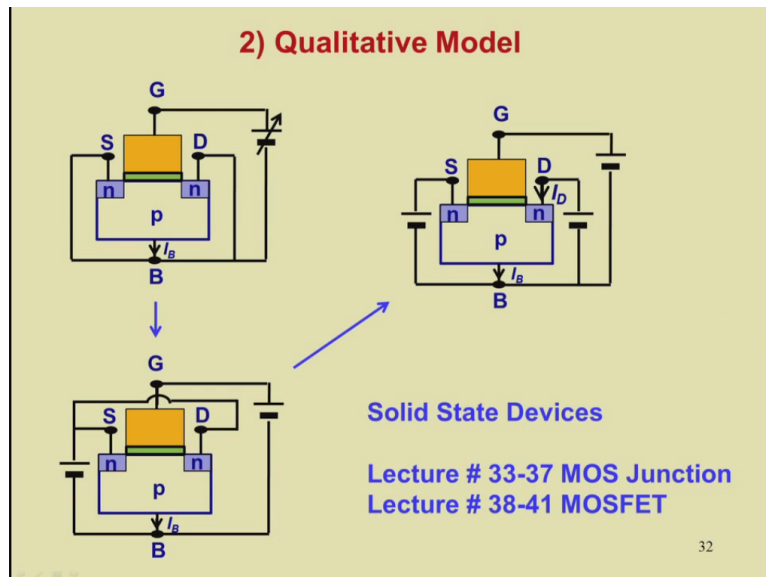
**(Refer Slide Time: 16:12)**



Now let us look into the charge conditions in the MOSFET for the biasing arrangement that we discussed. For gate to bulk voltage more than a value known as a threshold voltage, you have inversion layer of mobile electrons at the interface in an N-channel MOSFET. Beneath the inversion layer, you have a depletion layer from which all carriers are depleted out. Now for sufficiently large value of  $V_{GB}$  or  $V_{TB}$ , you have a significant current flowing from drain to source if  $V_{DB}$  is more than  $V_{SB}$ .

The inversion layer charge progressively decreases from source to drain as indicated here and the depletion layer charge increases from source to drain as indicated here. Now how does this happen? This is what we need to explain in our qualitative model. To explain the charge conditions in a MOSFET, which has all the 3 biases namely  $V_{GB}$ ,  $V_{DB}$  and  $V_{SB}$ . What we do is we proceed in the following steps.

**(Refer Slide Time: 17:28)**



First we analyze the charge conditions in a MOSFET in which only  $V_{GB}$  is applied.  $V_{SB}$  and  $V_{DB}$  are shorted. This is a simple situation. So after this analysis, we move on to analyzing a device in which there are 2 biases  $V_{GB}$  and  $V_{SB}$ . The  $V_{DB} = V_{SB}$  as shown here so drain and source are shorted therefore there is no drain to source current in this case.

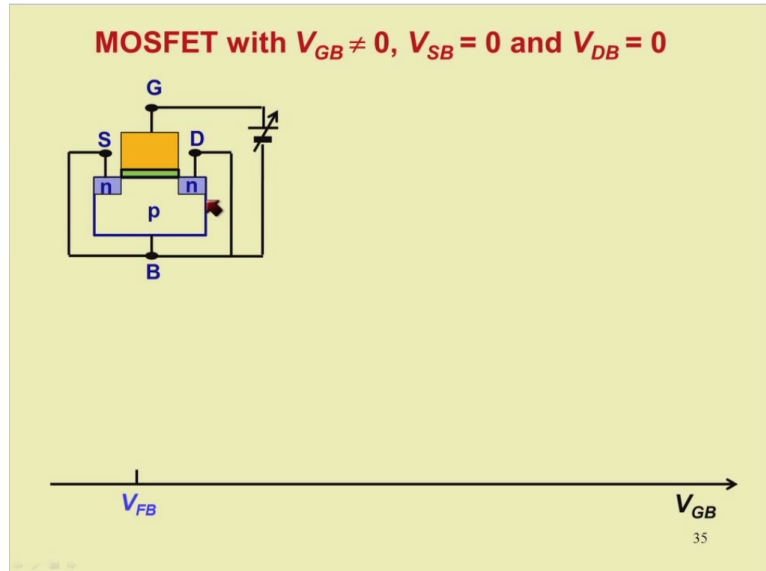
So in other words we have  $V_{GB}$  and then we have introduced another voltage  $V_{SB}$  that is reverse biased source and drain with respect to bulk and then we analyze how the charge conditions get modified. In the third step, we separate the source and drain and bias the drain positively with respect to bulk as shown here and if you have  $V_{DB}$  more than  $V_{SB}$  then you have a drain current flowing. So then we analyze this structure.

Now in a previous course titled solid state devices which is available in YouTube, I have discussed details of charge conditions in all the 3 cases here in to following lectures. So lecture 33 to 37 titled MOS junction discusses the charge conditions in a MOSFET for these 2 biasing arrangement and the lecture 38 to 41 titled MOSFET discusses the charge conditions in this biasing arrangement.

In other words, a first level model of the MOSFET is available in this basic course titled solid state devices available in YouTube. So I would encourage you to view these lectures before proceeding further. However, for the sake of convenience I am going to summarize some important points from these lectures in the present lecture so that we can proceed further and develop a more complete model of the MOSFET.

In the first level course on solid state devices, we have a first level model of the MOSFET. This is an advanced course so we would like to go beyond what we discussed in the first level course.

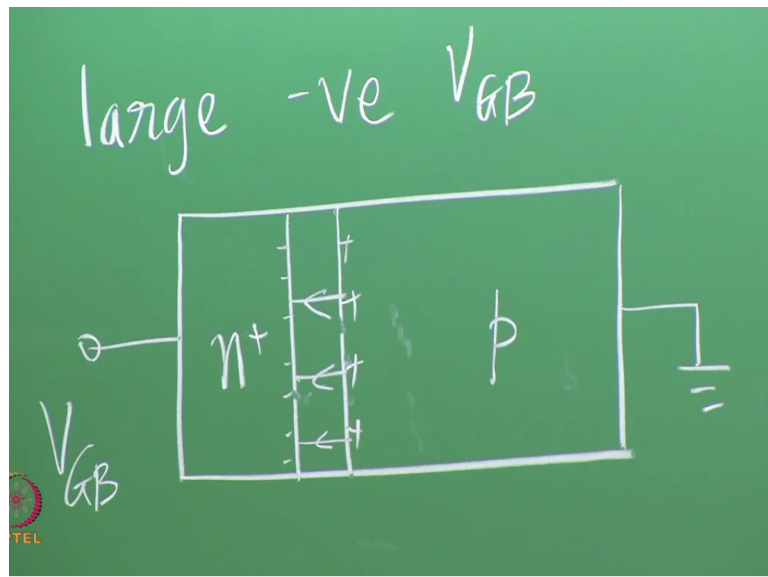
**(Refer Slide Time: 19:59)**



Now here is the summary of this important features. Let us begin with a MOSFET with  $V_{SB}$  and  $V_{DB} = 0$ , but  $V_{GB} \neq 0$ . Let us draw a line indicating the  $V_{GB}$  axis, the first important point we get on this axis is the so called flat band condition and the voltage corresponding to that is the flat band voltage. Now let us explain what is this condition? In our explanation, we shall be concentrating on this central part of the device okay here which means we will be ignoring the source and drain junctions and the associated depletion regions here.

This is because it is a large MOSFET and the distance between the source and drain is very much large compared to the depletion widths in the substrate from source and the depletion width in the substrate from the drain.

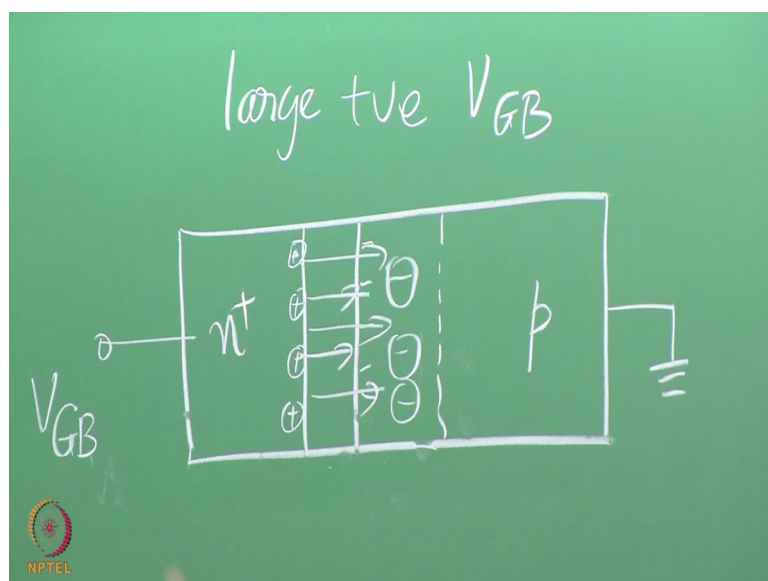
**(Refer Slide Time: 21:10)**



Now we will draw the MOSFET in such a way that your gate terminal is to the left and the bulk is to the right. In other words, as compared to this diagram here, I am going to turn the MOSFET 90 degrees, move this gate to the left so that the bulk comes to the right. The reason for that is we would like to plot various charge-field conditions in the device and those conditions are best plotted with one axis, the spatial axis the distance horizontal.

Now consider the case of large negative  $V_{GB}$ . If  $V_{GB}$  is very large and negative, you have a negative charge here because of electrons and positive charge because of holes. See you have a field directed like this.

**(Refer Slide Time: 22:37)**

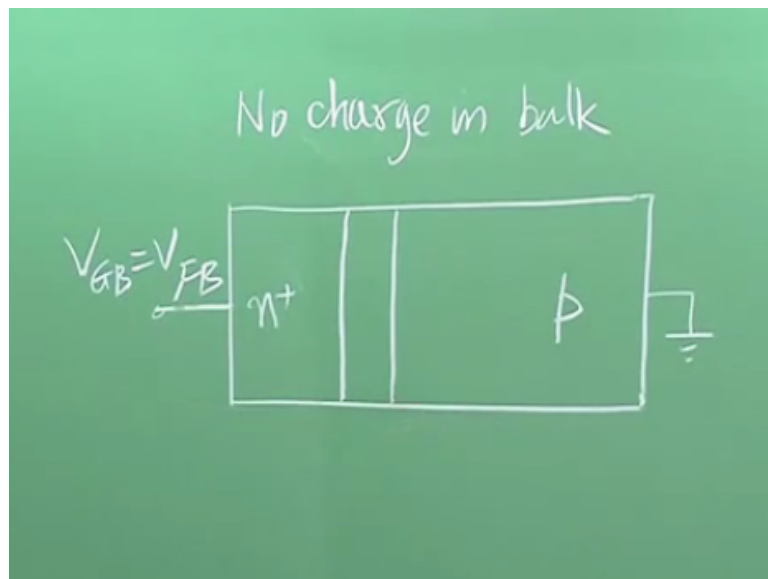


If I consider large positive voltage, then the conditions would be as follows. So here you will have a positive charge on the gate, the positive charge can be created by removing some

electrons from here and exposing the ionized donors and here you can get a negative charge by attracting the electrons to the surface, but electrons are minority carriers so you can get a negative charge by depleting the holes, moving away the holes because the field is like this.

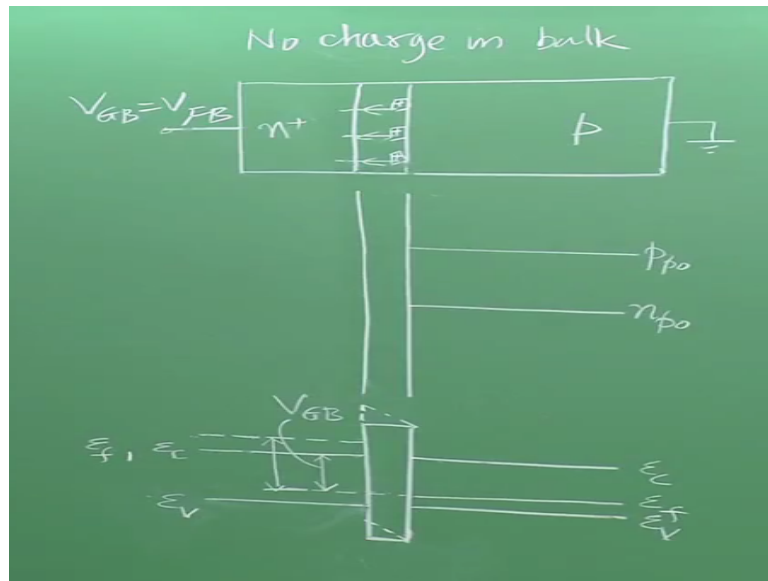
This field can drive away the holes leaving behind a region of no holes and electrons can be attracted to the surface. So you can have a negative charge in this case. So evidently between large positive VGB and large negative VGB you have a condition when there is no charge in the substrate. Let us show that here.

**(Refer Slide Time: 24:05)**



So this is  $V_{GB} = V_{FB}$ . So here no charge in bulk or substrate. Now does it mean no charge in the gate? We will come to that point shortly. Let us first talk only about no charge in the substrate. Why should this condition be called flat band okay? For that we have to draw the band diagram in the piece of state for this condition.

**(Refer Slide Time: 25:03)**



Now before that let us draw the concentration. So if I am going to draw the concentration, if there is no charge that means the hole concentration remains =  $p_{p0}$  and electron concentration remains =  $n_{n0}$  because the substrate is uniformly doped no charge means that the carrier concentration is constant. Please note, that if this is non-uniformly doped, carrier concentration would not be constant even if there is no charge okay.

Because hole concentration and electron concentration will change according to the doping. Now let us come to the band diagram. So this is your  $E_C$  and this is your  $E_V$  and this is your  $E_F$ , it is a p-type substrate so bands are flat. Because the bands are flat it is called a flat band point right. If the concentration is constant then  $E_C$  and  $E_V$  levels are all constant because  $E_F$  is constant under equilibrium, no current is flowing here right.

Because there is oxide in between  $n^+$  and  $p$ , no current flows this under equilibrium. Now let us complete this picture and draw the bands on the  $n^+$  side. On the  $n^+$  side, the bands would look like this. This is  $E_C$  and we will assume that the doping here is so heavy that the Fermi level coincides with  $E_C$ . So this is your  $E_V$  and this line should be exactly next to this because energy gap is same for both substrate and gate.

Now this is the band picture in the  $n^+$  region. Now this picture will tell you why the flat band voltage can be non-zero. So you see the Fermi level in the gate is not at the same level as Fermi level in the substrate. Let me also show the conduction band and valence band in oxide for the sake of completeness. This diagram is not to scale okay. So this is your  $E_C$  in oxide and this is your  $E_V$ .



So evidently to achieve this condition, you have applied a voltage equal to the difference in the Fermi levels that is this. So the gate to bulk voltage for this condition is equal to the difference in Fermi level for this condition, which is this, which is the flat band voltage. So this is your VGB. So please note how did we come up with this condition? First we said that we want condition of no charge in the substrate and no charge in the substrate means bands are flat, it is like this.

Then we drew the corresponding band picture in  $n^+$  side, here also the bands are flat and then because the doping here is different from doping here Fermi level here was different from the Fermi level here. Then from the difference of the Fermi levels, we concluded about the gate bulk voltage to be applied to achieve this condition. So this explains why VFB can be non-zero.

Another reason VFB can be non-zero is because of the fixed charge in the oxide substrate interface. Now because of this fixed charge what happens is the following. If I do not want any charge in the substrate for some gate to bulk voltage it means that this positive charge cannot terminate on negative charge in the substrate. So where will the field lines from this positive charge terminate in that case?

They have to terminate on the gate. Now this means there is a field in the oxide. Now here we have drawn the conduction band of the oxide flat, there is no field in the oxide. This is very interesting please remember. In the absence of this positive charge, though we have applied a gate to bulk voltage there is no field in the oxide because there are no charges. Now however there is a field, this field is directed from substrate to gate.

Substrate is positive, I mean the interface towards the substrate is positive and interface towards the gate is negative you can see that from here. This means in energy band picture, your energy band in the oxide will be like this, something like this right. This band bending indicates the field and you know that in energy band diagram, the higher you move the more negative you go because these are electronic energies.

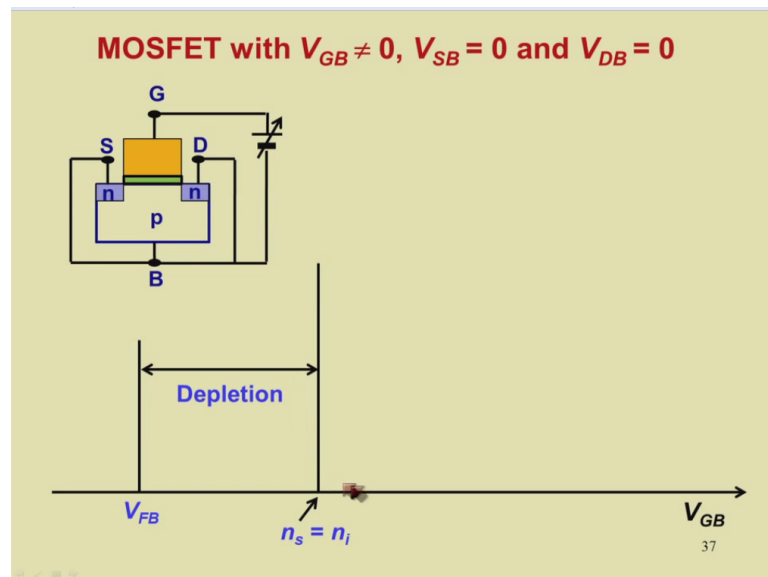
So the lower end is positive, the higher end is negative okay. So you can now complete the same thing for valence bandage. Now for this case if you want to draw the band picture in  $n^+$

when the positive charge is there, then I must lift this  $E_c$  up by the same amount as this because the difference between the conduction bandage in the oxide and the conduction bandage in poly are difference between the conduction bandage in the oxide and the conduction bandage in the substrate.

These differences are decided by the difference in materials. They do not change with bias. So for this case if I want to show, my  $E_c$  will go up, this  $E_c$ ,  $E_f$  line would be here. Now since this has moved up, the amount of gate to bulk voltage you have to apply to get this condition is this. So you can see that the gate to bulk voltage has increased now to provide negative charge okay to compensate for this positive charge with increase in the negative direction whatever.

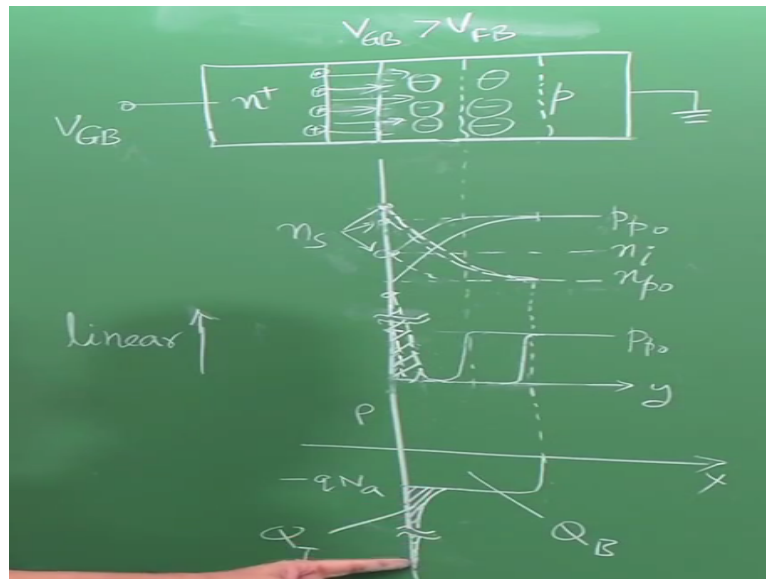
So this is the new flat band voltage including the Fermi level differences in the gate and substrate and the effect of the positive charge. I have not drawn the  $E_v$  here, you can draw it to avoid cluttering. The  $E_v$  will be exactly  $E_g$  below this  $E_c$  and  $E_f$ . Now this also called flat band condition okay.

**(Refer Slide Time: 32:32)**



Now that is the condition we have shown here. To the left of the flat band, you have condition called accumulation where there will be positive charge accumulating at the interface. On the other hand, on this side if you go which is of interest to us, you have accumulation of negative charge okay. Now as you increase  $V_{GB}$  beyond  $V_{FB}$ , we will encounter a state where the surface constant of electrons =  $n_i$  and the region between  $V_{GB}=V_{FB}$  and the value of  $V_{GB}$  for which  $n_s=n_i$  is normally referred to as depletion.

(Refer Slide Time: 33:28)



Let us see why? Now let us consider this case because your  $V_{GB}$  is more than  $V_{FB}$ . So instead of large positive  $V_{GB}$  we will say  $V_{GB} > V_{FB}$ . Now let us see the condition when you have a small  $V_{GB} > V_{FB}$ . Now how do you get the negative charge? So you can drive away holes and attract electrons both. Let us show that. So this is your  $P_{p0}$ , this is your  $N_{p0}$ .

For some voltage you have this condition gate voltage. This is  $n_i$ . We are plotting concentrations on a log scale, so  $n_i$  is in between  $P_{p0}$  and  $N_{p0}$  exactly in between on the log scale. This is your  $n_s$ , surface constant of electrons, so you see what is happening, electrons have been attracted to the surface that is why the concentration is rising, holes are being driven away from the surface so their hole concentration is falling.

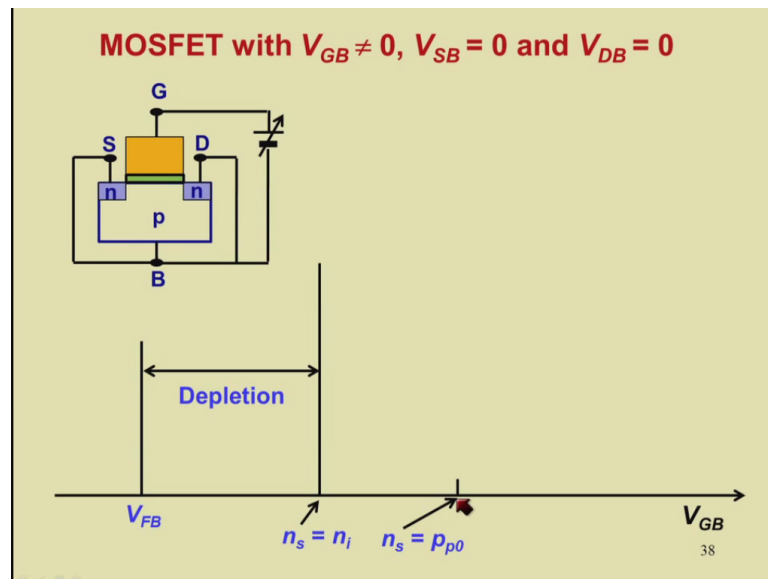
So that is the condition,  $n_s = n_i$  for some value of voltage. Now why is this region called depletion? Because you can see here if I were to sketch the same concentration on the linear scale, this is my  $P_{p0}$  and this is your y axis right, let us say this is this direction. We calling it y because in the diagram here our MOSFET is shown with gate on the top and bulk at the bottom therefore this direction from gate to bulk is vertical and this is y.

So we have plotted  $P_{p0}$  on the linear scale here this was on the log scale. Note that on the log scale, difference between  $P_{p0}$  and  $N_{p0}$  is many orders of magnitude. For example, if  $P_{p0}$  is  $10^{17}$ ,  $N_{p0}$  would be  $10^3$ . So  $17$  to  $3$ ,  $14$  orders of magnitude increase in carrier concentration when you go up. Therefore if you move even a little bit, your carrier

concentration would have fallen by a factor of 10 that is on the linear scale it will appear very rapid fall. So let us emphasize this fact and say this is linear.

It is understood that this is log because otherwise I cannot show  $P_{p0}$  and  $N_{p0}$ . Now what about electron concentration? You see  $n_i$  is of the order of  $10^{10}$ , this is suppose  $10^{17}$ ,  $10^{10}/10^{17}$  is  $1/10^7$ . So if I want to show this  $n_s$  here, concentration here is  $10^7$  times less than this. I really cannot show. So on a linear scale I cannot show this electron concentration.

**(Refer Slide Time: 37:23)**

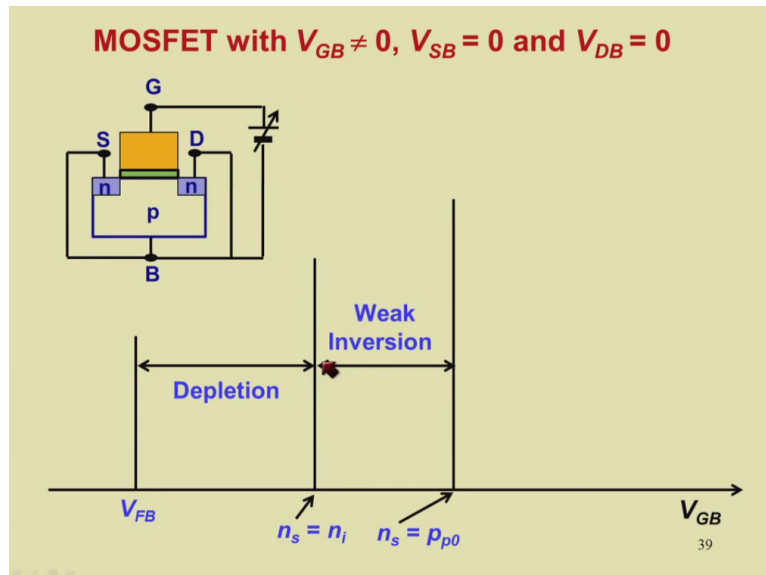


That is why you can see we can regard this region as depleted of both holes and electrons as you can see from here, hole concentration is very small, electron concentration also very small that is why this is the depletion region and that is why this region here is referred to as depletion. Suppose we increase  $V_{GB}$  further, we will encounter a situation when the surface concentration becomes  $= P_{p0}$  that is the concentration of holes in the bulk.

Did I show that here? So this is the case when  $n_s = P_{p0}$ . Both these are  $n_s$ . Now if you try to show this picture here how would it look. Now  $n_s = P_{p0}$  so you have  $n_s$ , but then once again here this variation in electron concentration is several orders of magnitude even if I move a little bit inside my electron concentration would have fallen by a factor of 10 right because this is 14 orders of magnitude variation and therefore on the linear scale this concentration would look something like this. This is your  $n_s$ .

So you do not have too many electrons. The whole picture would look something like this. So in other words, your depletion region has expanded. Depletion charge has increased. If I were to show the hole concentration here, it would be like this. So when  $n_s = p_{p0}$  this is your hole concentration, this is your electron concentration, this is the same thing on a linear scale.

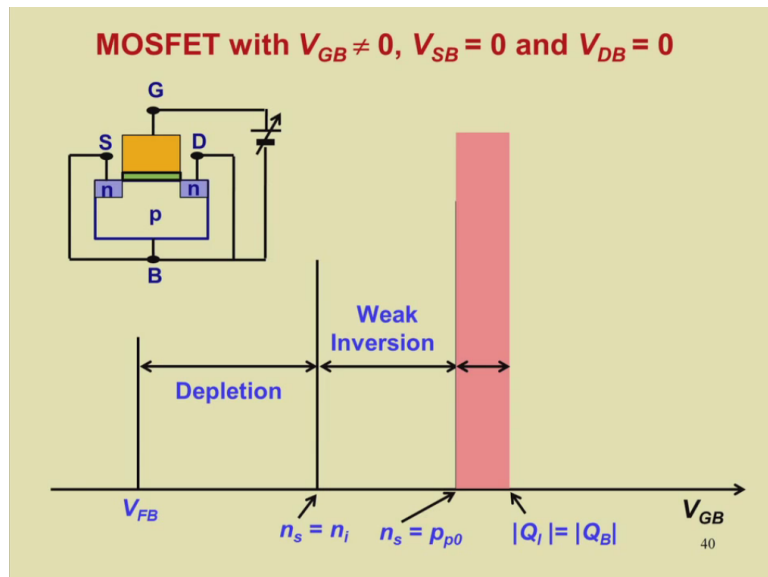
**(Refer Slide Time: 39:23)**



Now this region is referred to as weak inversion region from  $n_s = n_i$  to  $n_s = p_{p0}$ . It is inversion because you can see here that once  $n_s$  becomes more than  $n_i$ , you can regard the surface to have become more n-type right. Now the interface becoming n-type in a p-type substrate means the surface has got inverted. So inversion starts here. So this inversion, but then if you take the amount of inversion charge you see when you plotted on a linear scale beside that for  $n_s = n_i$  I cannot show the electron concentration at all.

For  $n_s = p_{p0}$  I can show some concentration and this is your inversion charge. However, if I compare this inversion charge that is area under this curve shown by the shaded line with the depletion charge which is equal to this area amount of holes removed, amount of holes depleted that is this area. So this shaded area is very small compared to this area. Therefore, the inversion charge is really very small therefore it is referred to as weak inversion.

**(Refer Slide Time: 40:39)**



If you increase  $V_{GB}$  further, you will encounter a situation where the inversion charge will be equal to the depletion charge. Now let us sketch that here. You increase  $V_{GB}$  further, so inversion charge now this in electron concentration will be increased further. It turns out that the depletion charge does not increase much beyond this point. This has been proved by numerical calculations also.

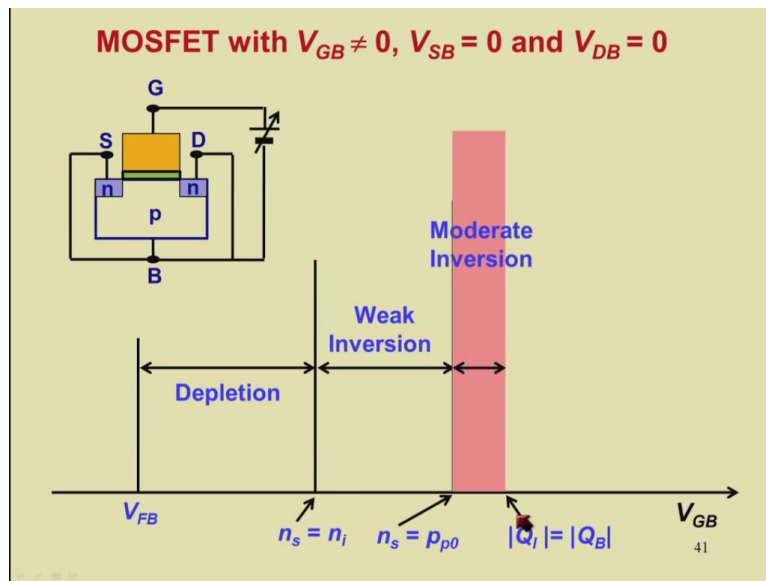
That is why the starting point of this rise in electron concentration is being shown approximately at the same point okay for  $n_s = p_{p0}$  and  $n_s$  more than  $p_{p0}$ . So for this case, if I were to plot the electron concentration here note that small increase on a log scale means a high increase on a linear scale because this may be even 100 times increase so I really cannot show it to scale because 100 times increase means from here to you know much above

So what I do is I put a break here and then your electron concentration would be something like this on the linear scale. Now this is your  $n_s$ . Similarly, this is your  $n_s$ . If I now take the inversion charge for this case that would be this shaded area, which is now quite a bit. For some condition, this shaded area will become equal to the holes depleted that is this area okay. So that is when you say  $Q_i = Q_B$ . Now let me show that by plotting the space charge.

I will plot the space charge only for this condition when  $n_s$  is more than  $p_{p0}$ . So this is the depletion charge this is  $-qNa$  that is because of this and because of electrons here if I want to show the charge that would be going up like this. Again here I have to show a break because this is really electron concentration is very high compared to this and this is the shaded area.

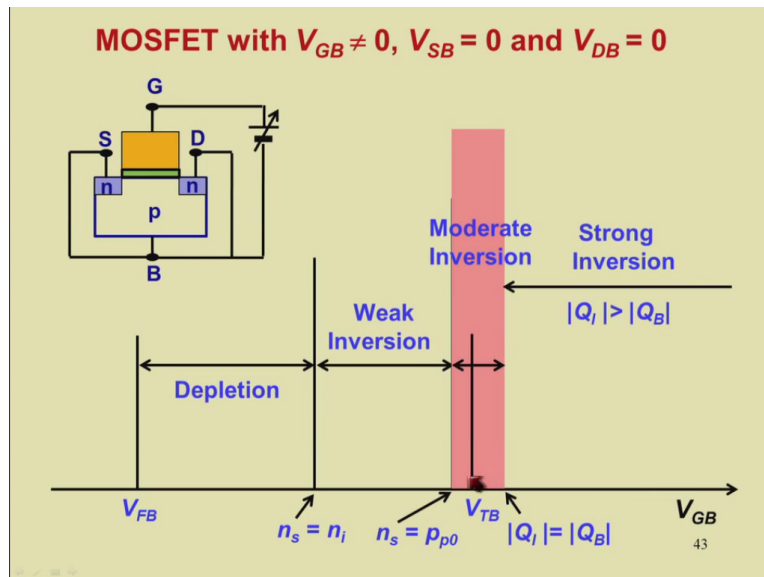
That is the space charge because of electrons inversion so this is  $Q_I$ , this is  $Q_B$  this region. So we are saying this area is equal to this shaded area that is  $Q_I=Q_B$  that is the condition. Evidently, here if I want to show this here it would be something like this depletion region has expanded and you will have a large number of electrons coming here so this field will be more you know if you are going to hire an hire voltages for this case and this case if I want to show the conditions here the depletion region will be more and more electrons will come here.

**(Refer Slide Time: 44:03)**



Now region between these 2 points when  $n_s=p_{p0}$  and  $Q_I=Q_B$  is referred to as the moderate inversion region. Note that this point is expressed in terms of the volume concentration of electrons at the surface whereas this point is expressed in terms of the area concentration of electrons inversion charge okay this is important to note. So  $n_s$  is the volume concentration of electrons so it is the volume concentration of electrons at a point, but  $Q_I$  is the area under the distribution okay it is an area.

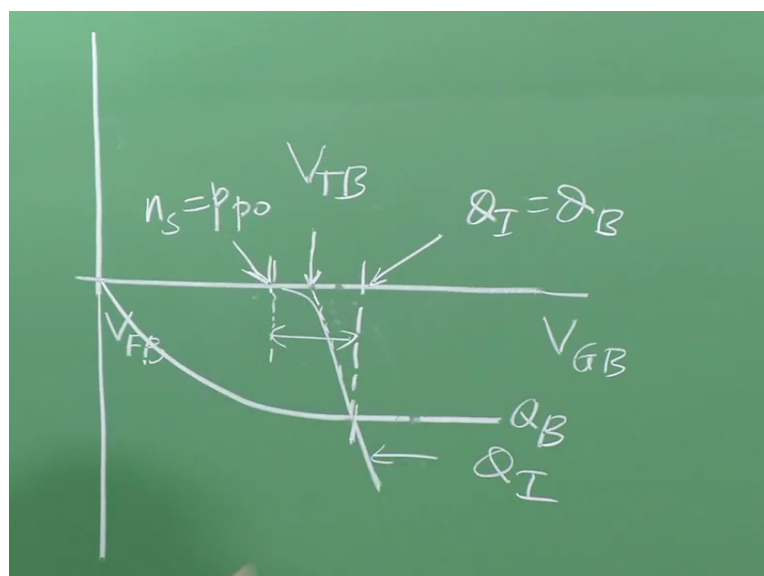
**(Refer Slide Time: 44:49)**



Now this region is called moderate inversion and when  $Q_I$  is more than  $Q_B$ , the range of  $V_{GB}$  here is referred to for this range of  $V_{GB}$  the device is referred to be in strong inversion because the surface has become strongly n-type as compared to the bulk, which is p-type. In the moderate inversion, you have the voltage called the threshold voltage. Now we are putting a suffix B here because the gate voltage is with respect to bulk.

Let us see what is this threshold voltage? If I plot this inversion charge that is this area shaded area or this area, as a function of the  $V_{GB}$ , the picture would look something like this.

**(Refer Slide Time: 45:39)**



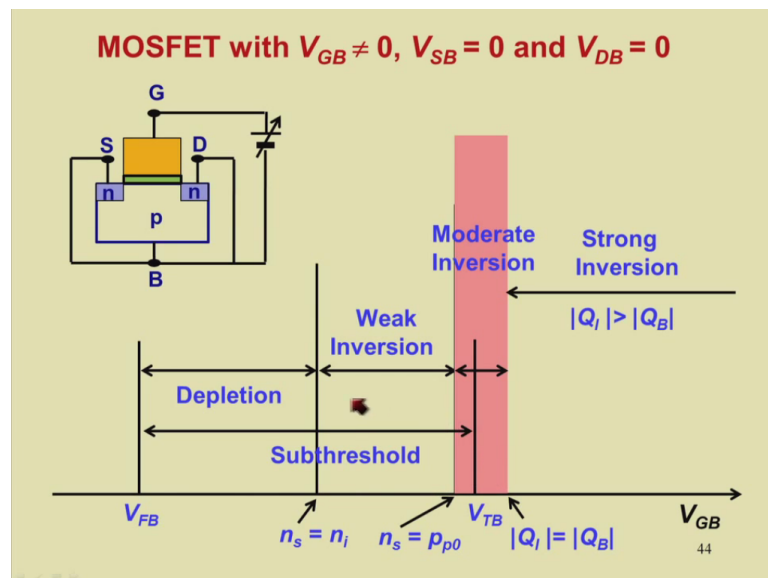
So the inversion charge will be very small for  $V_{GB}$  beyond  $V_{FB}$  so this is let us say  $V_{FB}$ . This point is  $V_{FB}$  and beyond some voltage, it will start rising and the rise will have a linear part. If I extrapolate this linear part, so this is  $Q_I$  they are showing on a negative side because



QI is negative. This voltage extrapolated voltage  $V_{GB}$  is referred to as the threshold voltage. To see the location of this threshold voltage clearly let me also show the  $Q_B$  variation on the same graph. So this is  $Q_B$ . You can say this is the point where  $Q_I$  and  $Q_B$  are becoming equal. If I were to sketch the condition when  $n_s = p_{p0}$  that is this condition  $p_{p0}$  the inversion charge is there, but is very, very small that would be somewhere here.

So this condition is  $n_s = p_{p0}$  and this condition is  $Q_I = Q_B$ . So this is the so called moderate inversion region. So you see that the threshold voltage falls in the moderate inversion region and is located as the gate to bulk voltage obtained by linearly extrapolating the  $Q_I$  versus  $V_{GB}$  graph to the  $V_{GB}$  axis.

**(Refer Slide Time: 47:33)**



The region from  $V_G = V_{FB}$  to  $V_G = V_{TB}$  is referred to as subthreshold that is below threshold. With that we have come to the end of the lecture so let us make a summary of the important points.

**(Refer Slide Time: 47:45)**

## Summary of the Lecture

In this lecture, we have begun a discussion of the qualitative theory behind the DC characteristics of a large uniformly doped bulk MOSFET. We remarked that while this device is used with source as a common terminal in a circuit in other words the voltages to the various terminals of the device are applied with respect to the source in a circuit when you want to develop a device model starting from device physics biasing this MOSFET with respect to bulk as a common terminal is more convenient.

Then we said that in practice a MOSFET is biased with 3 voltages. One between drain and source, another voltage between gate and source and at times a voltage between bulk and source. A model for this biasing arrangement is developed starting from the simple case of a MOSFET to which only a bias is applied between gate and bulk, source and drain junctions are shorted to the bulk.

So in effect this becomes a 2 terminal device so we understand the charge conditions in a 2 terminal device. Then we try to understand the charge conditions in an effectively 3 terminal device in which 2 voltages are applied, one between gate and bulk, another one between source and bulk. We assume the drain to bulk voltage to be same as source to bulk voltage.

After understanding the charge conditions in a MOSFET for this situation where you have 2 voltages applied we move to the MOSFET with all the 3 voltages applied. We remarked that in an earlier course called solid state devices, which is available on YouTube we have discussed various charge conditions in a MOSFET and the theory underlying the MOSFET operation at a very fundamental level or level 1 in lectures 33 to 41.

So you are encouraged to go through those lectures before proceeding further. However, for those people who are already somewhat familiar with MOSFET theory what we have done is we summarized in this lecture some key points from this previous course. So that we can move further and develop a more advanced model of the MOSFET. The key points we summarized related to identification of the accumulation, depletion, weak inversion, moderate inversion and strong inversion regions.

So we identified the gate voltages, which help us to delineate these various regions of operation. The important gate to source voltages or rather gate to bulk voltage because we said that we discuss a device with bulk as the common terminal. So we identified important gate to bulk voltages, which help us in delineating the MOSFET regions like depletion, accumulation, inversion and so on.

The important voltages are the flat band voltage and the threshold voltage. In between, you have some other voltages also which we discussed. In the next lecture, we will consider the effect of a bulk to source reverse bias and then discuss the case when you have bulk to source, source to bulk, gate to bulk and drain to bulk voltages.